



Electronic *CAD & Reliability* Group

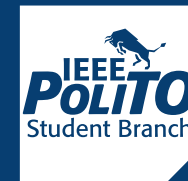
# Estimating the reliability of DNNs regarding permanent faults on GPUs

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**PhD**  
**itch**  
the PhD's pitch



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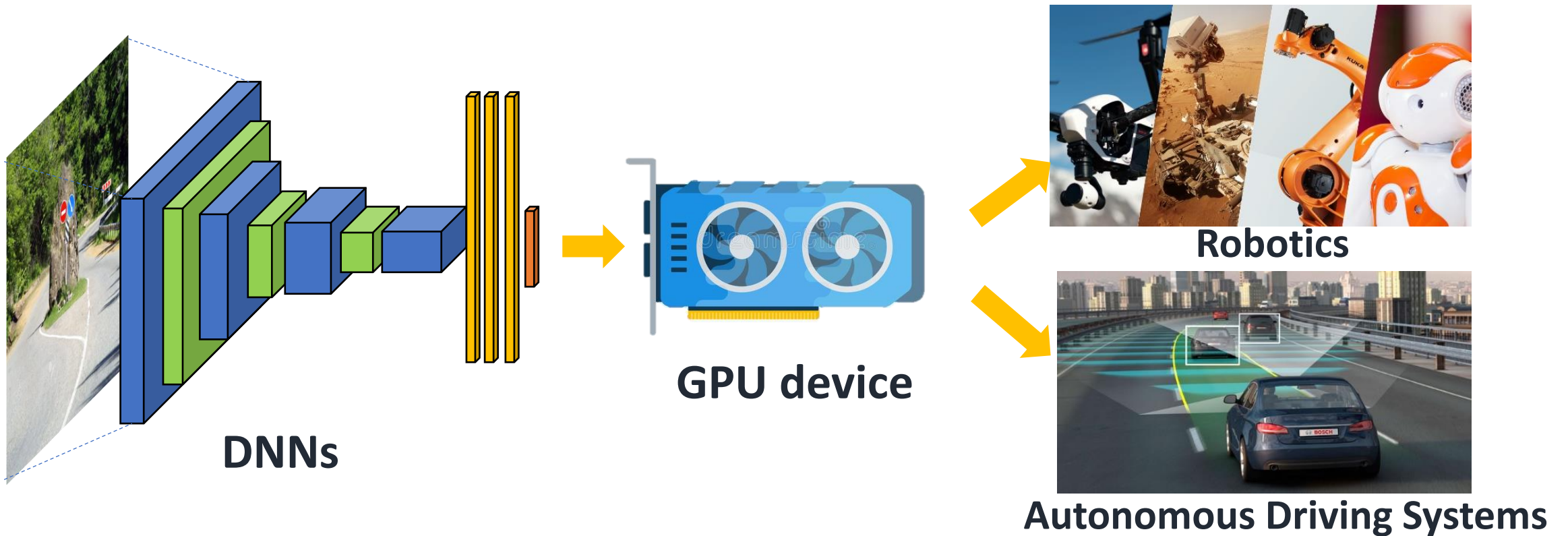


# Outline

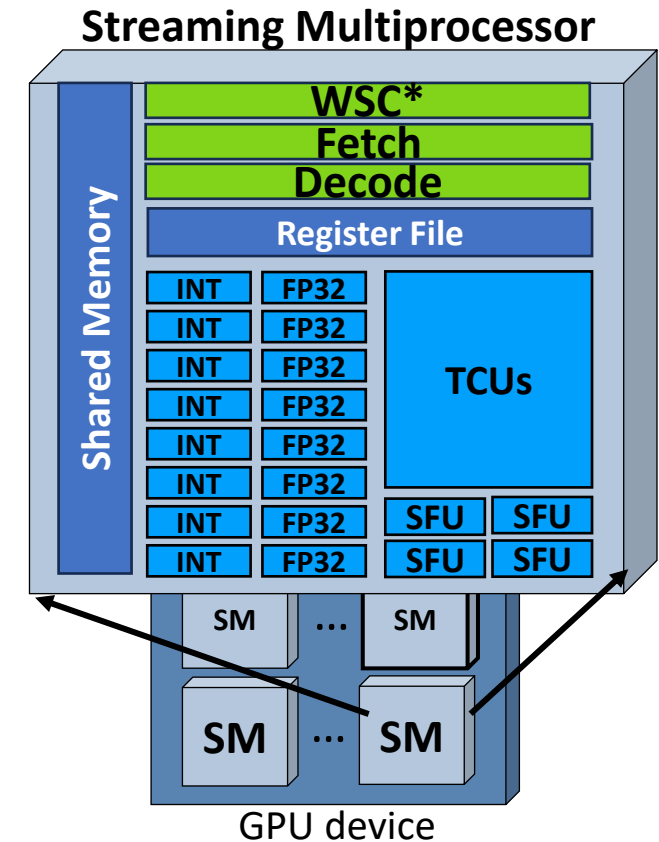
- **Introduction and background**
- Evaluation methodology
- Experimental results
- Conclusions.

# Introduction

**Graphic Processing Units (GPUs)** are widely used as **AI accelerators** for deploying **Neural Networks** in **safety-critical applications**

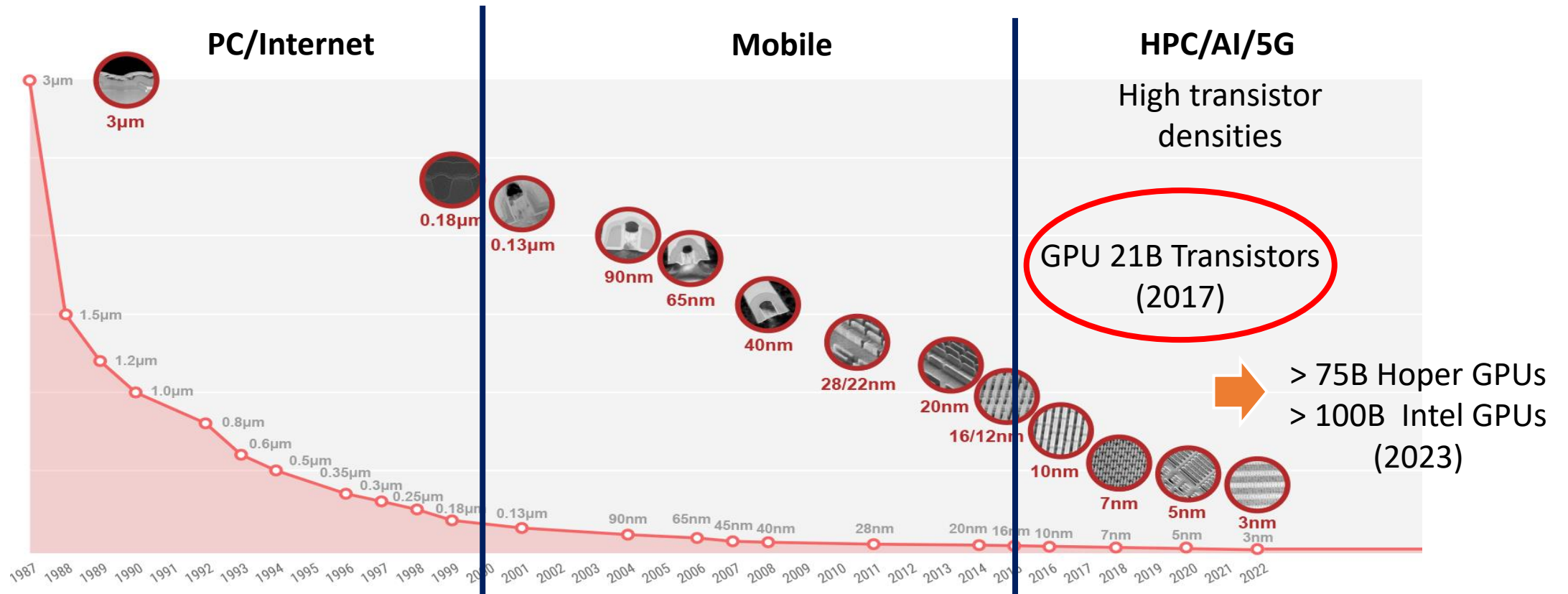


- **GPUs** are composed of a **hierarchical interconnection** of **Streaming Multiprocessors (SMs)**
  - The SM comprises multiple units such as:
    - Control Units (Warp Scheduler, Fetch, Decode)
    - Scalar Units (INT, FP32)
    - Special Function Units (SFUs)
    - Tensor Core Units (TCUs)
    - Storage Units (Memories, Registers)
  - **Single Instruction Multiple Thread – SIMT**
    - Parallel Kernels (i.e., Cooperative Threads Arrays – CTAs)



# Introduction

- The application landscape has driven semiconductor technology evolution, including GPUs.



## Are modern chips reliable?

The New York Times  
*Tiny Chips, Big Headaches*

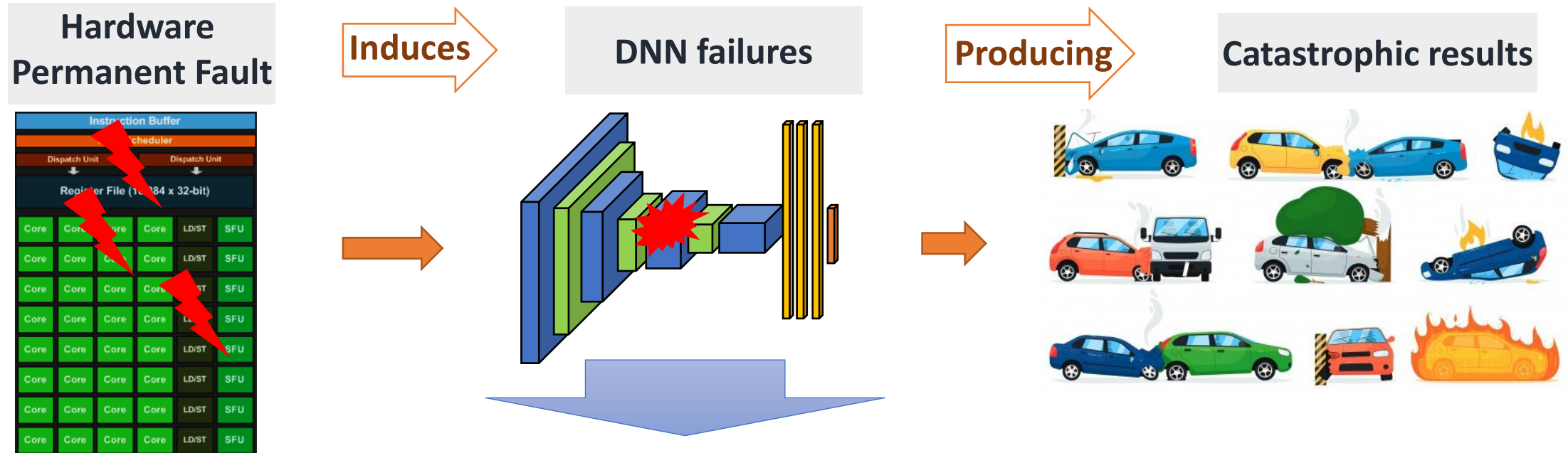
As the largest computer networks continue to grow, some engineers fear that their smallest components could prove to be an Achilles' heel.

- Modern **microelectronic devices**, including GPUs, can be affected by **hardware defects** caused by several phenomena:
  - Manufacturing defects
  - Material stress
  - Test Escapes
  - Environmental harshness
  - Wear-out
  - Aging

A **fault in a digital device** may induce **“Silent Data Errors” (SDEs)** at the application level producing undesired results and **jeopardizing the reliability** of the whole system

It is **crucial** to **assess the impact** of such **hardware faults** on the operation of **cutting-edge electronic devices**, in order to **devise** suitable **fault tolerance mechanisms**

# Introduction

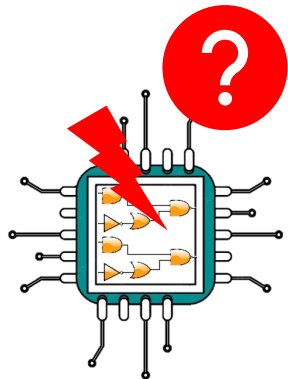
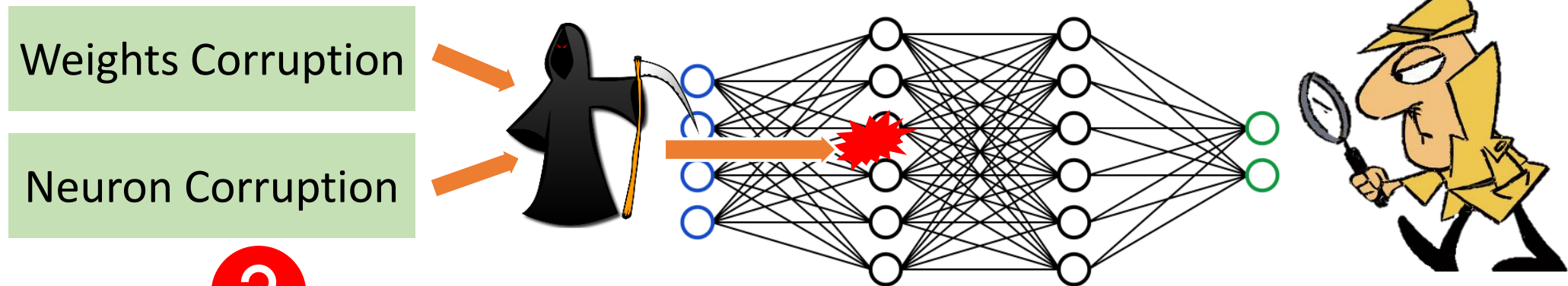


The **reliability** estimation of **DNNs** w.r.t. hardware **faults** in **GPUs** is mandatory to fulfill the requirements of the **safety standards** (e.g., ISO26262 for automotive domain).



# Introduction

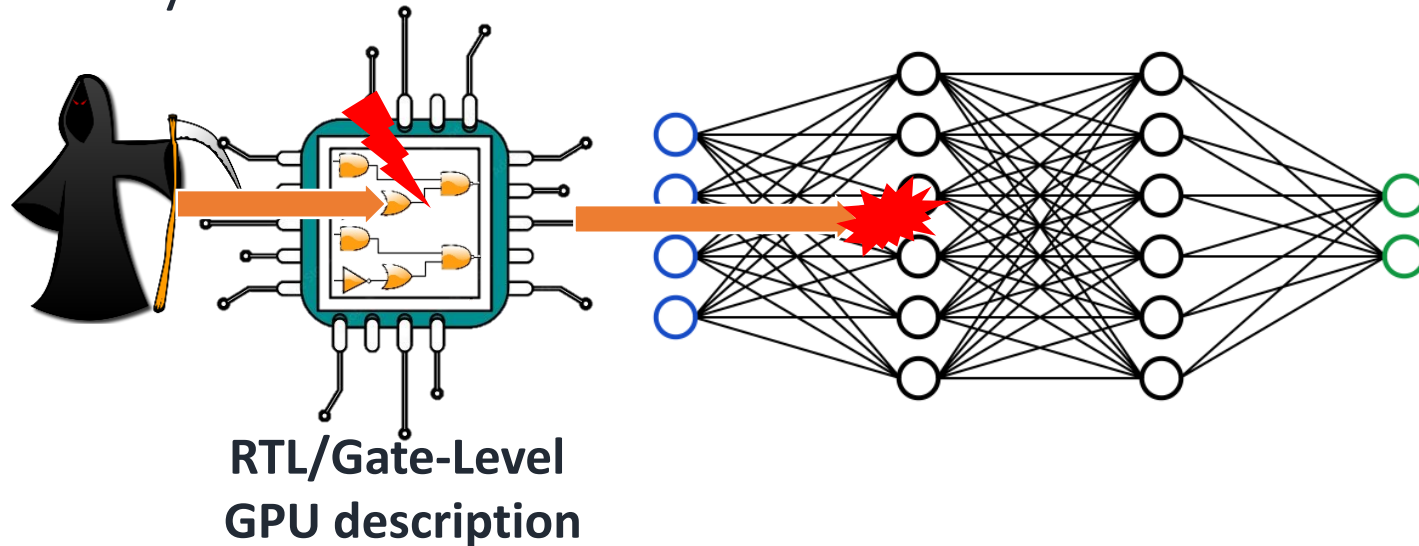
- The reliability estimation of DNNs w.r.t. PFs mainly resorts to Fault Injections (FI) at the application-level



**Unrealistic evaluations**

# Introduction

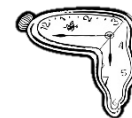
- Stuck-at
- Delay Faults



**> 10,000 days** for the  
evaluation of permanent  
faults on an **RTL-based**  
**GPU** model running  
**LeNet**



**Realistic evaluations**



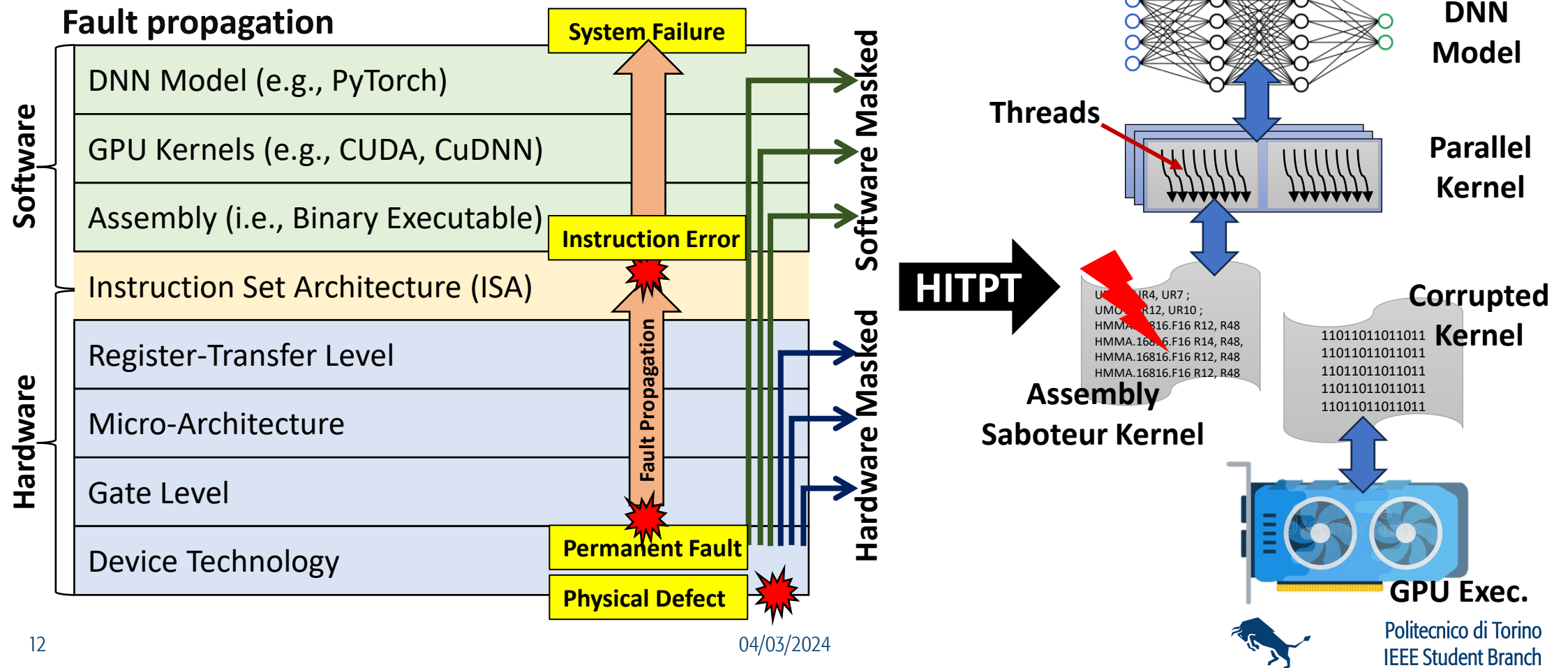
**Prohibitive Time**

# Outline

- Introduction and background
- **Evaluation methodology**
- Experimental results
- Conclusions.

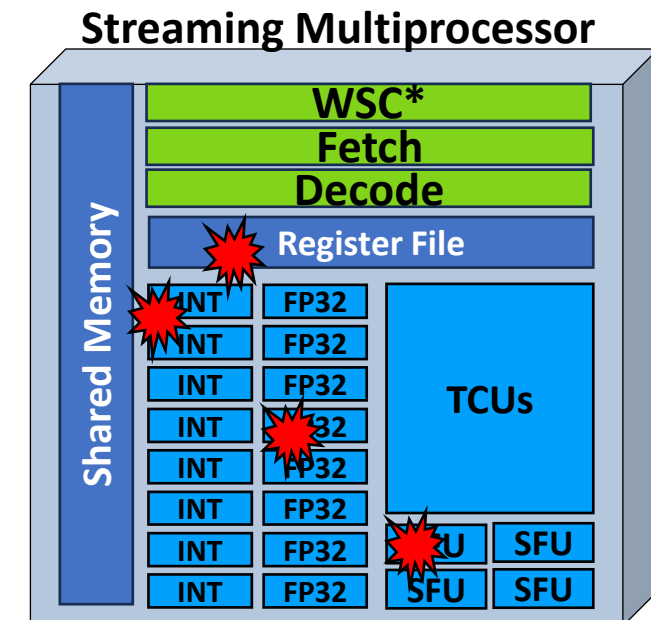
# Evaluation methodology

- **Hardware Injection Trough Program Transformation (HITPT)**



# Evaluation methodology

- This research proposes a HITPT methodology to evaluate the resilience of DNNs concerning permanent faults on GPUs
- The proposed approach insert saboteur functions at the instruction level of the GPU kernels
- Fault injections (FI) targets several GPU structures:
  - Register Files (RFs)
  - Integer Cores (INT)
  - Floating Point Cores (FP32)
  - Special Function Units (SFU)



# Evaluation methodology

Each fault is classified according to **its impact on the accuracy** of the DNN w.r.t. the fault-free scenario. The **Relative Accuracy Degradation (RAD)** metric indicates the degree of severity of the fault in the DNN.

$$RAD = \frac{ACC_{Gold} - ACC_{Faulty}}{ACC_{Gold}}$$

Faulty CNN's Accuracy

Fault-free CNN's Accuracy

## Fault classification

|  |  |
|--|--|
| <b>Device Unrecoverable Error (DUE)</b>      | GPU crashes or hangs   |
| <b>Silent Data Corruption (SDC-Critical)</b> | RAD > 0.0. At least one image was wrongly classified with respect to the fault-free scenario   |
| <b>Silent Data Corruption (SDC-Safe)</b>     | RAD = 0.0. The confidence prediction values for at least one image differ from the fault-free scenario but the classification is still correct |
| <b>Masked</b>                                | RAD = 0.0. No difference is observed between the faulty scenario and the golden one  |

# Outline

- Introduction and background
- Evaluation methodology
- **Experimental results**
- Conclusions.

# Experimental Results

- We developed a **prototypical tool** based on an improved version of the NVBitFI tool
- Four DNNs were evaluated using an RTX 3060TI GPU, NVIDIA Ampere architecture
  - **LeNet**: classifies images of **handwritten digits (0 to 9)** using the **MNIST** dataset
  - **AlexNet**: classifies images from **1,000 categories** from the **ImageNet** dataset
  - **DarkNet19**: classifies images from **1,000 categories** from the **ImageNet** dataset
  - **VGG-16**: classifies images from **10 different classes** defined by the **CIFAR-10** dataset.



# Experimental Results

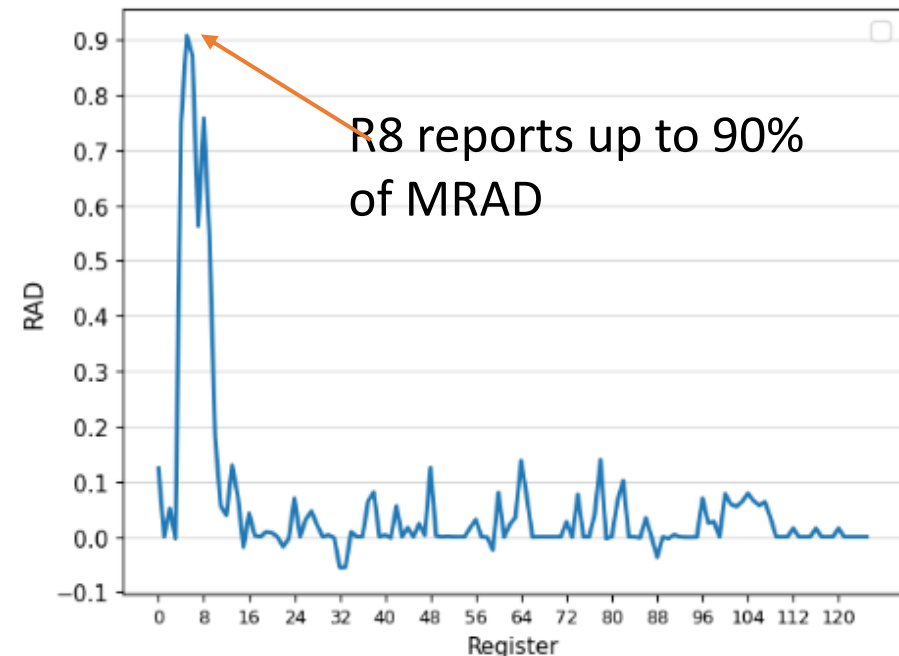
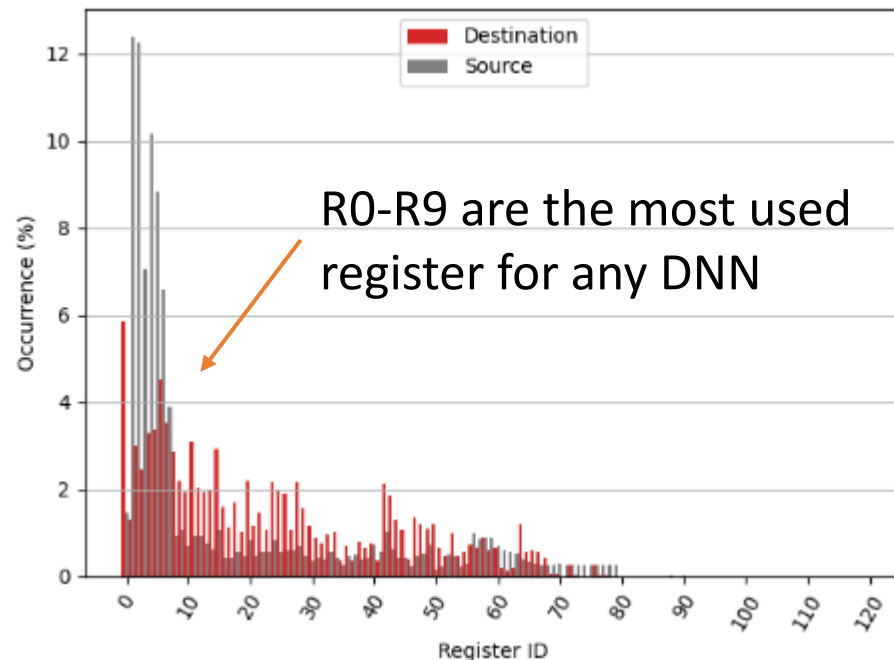
- Two fault injection (FI) campaigns
  - Exhaustive FI for all registers in one resident thread of an SM
  - Exhaustive FI for all instructions in one INT, FP32 and SFU core of an SM

| FI Campaign          | LeNet | AlexNet | DarkNet19 | VGG-16 |
|----------------------|-------|---------|-----------|--------|
| SM0, Warp0, Thread0  | 7,233 | 7,296   | 10,945    | 7,233  |
| INT_0, FP32_0, SFU_0 | 2,880 | 2,880   | 2,880     | 2,880  |

- Experimental evaluation takes around 107 Hours.

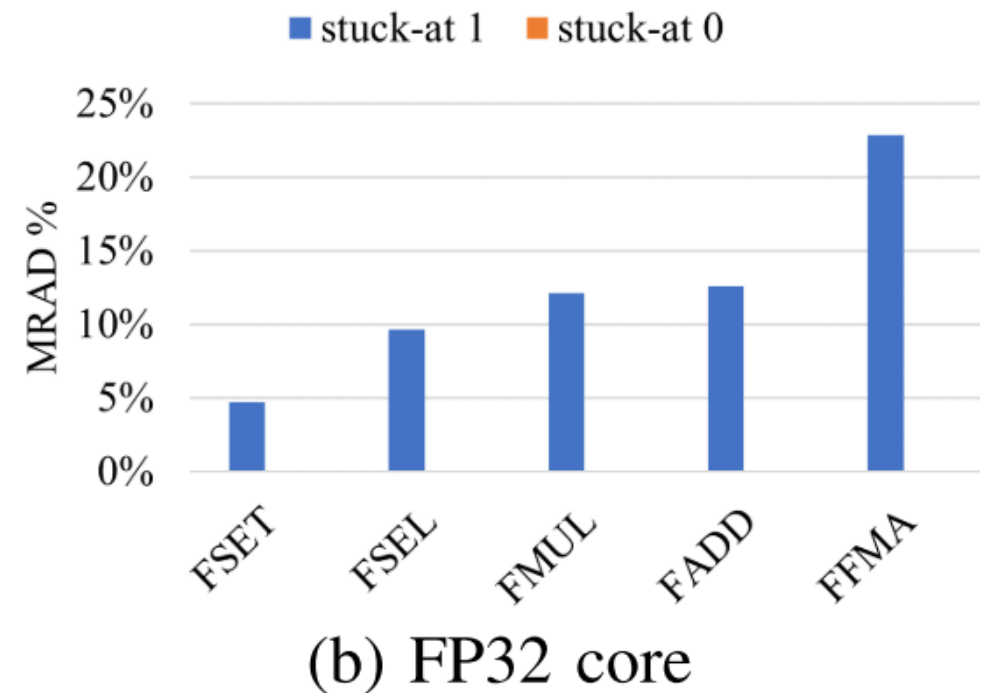
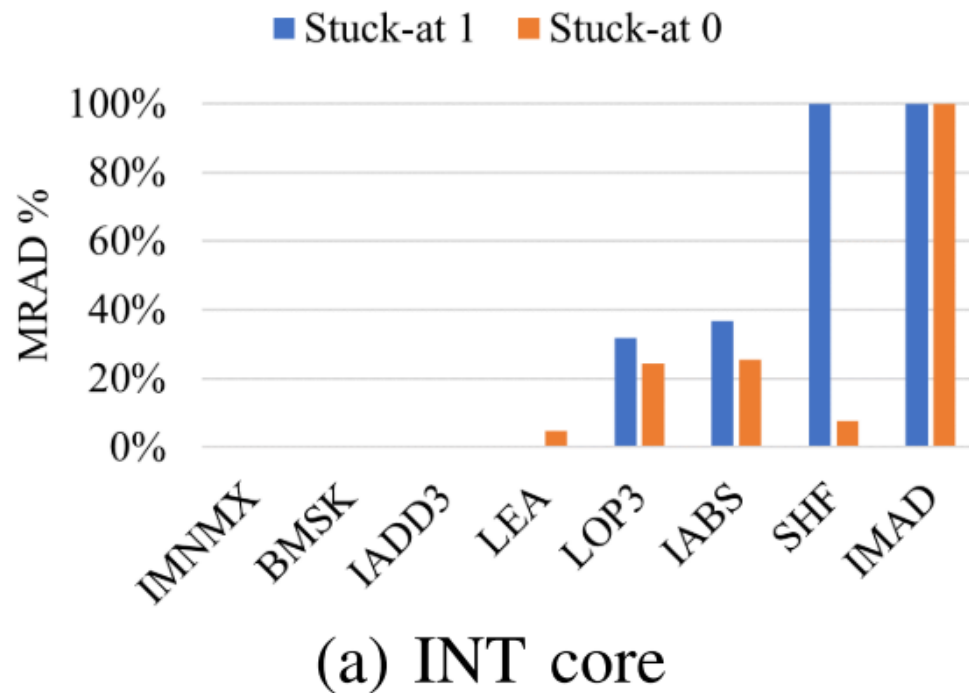
# Experimental Results

- The results show that faults in the first ten registers are the most critical, generating more than 20% of Mean Relative Accuracy Degradation (MRAD), and up to 90% of MRAD for R8.



# Experimental Results

- Stuck-at-1 faults lead to a higher impact on the DNN's accuracy for both integer and floating-point instructions than stuck-at-0 faults



# Outline

- Introduction and background
- Proposed fault injection methodology
- Experimental results
- **Conclusions.**

- This paper presents a **method for realistic evaluation of DNNs regarding permanent faults (PFs) in GPU devices**
- The **proposed solution** adopts the Hardware Injection Trough Program Transformation (**HITPT**)
  - Register Files (**RFs**)
  - Functional units (**INT, FP32, and SFU**)
- The results show that DNNs are highly sensitive to faults on the first ten registers per thread in a GPU
- **Stuck-at-1** faults on both INT and FP32 cores induce a high accuracy degradation in DNNs

# Future Works

- Future activities aim to devise effective hardening techniques to counteract the impact of permanent faults on the reliability of DNNs

Thank you!

Questions?

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